C. Materials Growth & Characterization 분과

2017년 2월 15일 (수), 10:10-11:40 Room G (코럴, 3층)

[WG2-C] Materials Growth & Characterization II

좌장: 권순용(UNIST), 박일규(서울과학기술대학교)

WG2-C-1 10:10-10:25	A Study of Atomic Layer deposited F-doped ZnO Transparent Conducting Oxides Thin Films Kyung-Mun Kang and Hyung-Ho Park Department of Materials Science and Engineering, Yonsei University
WG2-C-2 10:25-10:40	DRAM Poly/SiON Gate에서 Plasma Nitridation공정 최적화를 통한 NBTI 신뢰성 개선 이승미, 김형철, 조흥재, 장세억 SK하이닉스 미래기술연구원
WG2-C-3 10:40-10:55	Dislocation Deformation under High Compressive Growth Stress in GaN 양민호 ¹ , 유원택 ² , 조예원 ¹ , 백현석 ¹ ¹ Analytical Research Division, Korean Basic Science Institute, ² Center for Inter-University Research Facility, Kookmin university
WG2-C-4 10:55-11:10	Mechanical Hysteresis Study of VO ₂ Single Crystal Micro-Plate Grown by Reductive Phase Conversion Using Graphene Kyungchan Min, Dong Kyu Lee, Wook Jin Jeon, Young Ho Kim, and Hak Ki Yu Department of Materials Science and Engineering, Ajou University, Department of Energy Systems Research, Ajou University
WG2-C-5 11:10-11:25	Carbon-Doping of GaN Buffer Layer in AlGaN/GaN HEMTs on SI-SiC Substrate Kyeongjae Lee, Kwangsae Go, Jaeyeon Han, and Okhyun Nam Convergence Center for Advanced Nano Semiconductors (CANS), Department of Nano-Optical Engineering, Korea Polytechnic University